



AF/2621  
16/CHE  
PA 1-8-03

500.37149X00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: S. MAEDA et al.  
Serial No.: 09/294,137  
Filed: April 20, 1999  
For: DEFECT INSPECTION METHOD AND APPARATUS  
Art Unit: 2621  
Examiner: B. Werner

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AMENDMENT AFTER FINAL REJECTION

Box AF  
Assistant Commissioner for Patents  
Washington, D.C. 20231

December 16, 2002

Sir:

In response to the final Office Action of May 13, 2002, and the Office communication of May 24, 2002, and further to the Notice of Appeal of October 15, 2002, please amend the above-identified application as follows.

No additional claim fee is due in connection with the filing of the present amendment.

IN THE CLAIMS

Amend claims 7-8, 15, 22, and 27 as follows:

locally not defined